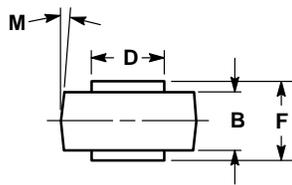
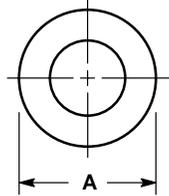


SCALE 1:1

MICRODE
CASE 193-04
ISSUE L

DATE 22 SEP 2003



NOTES:

- CASE 193-03 OBSOLETE, NEW STANDARD 193-04.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	8.43	8.69	0.332	0.342
B	4.19	4.45	0.165	0.175
D	5.54	5.64	0.218	0.222
F	5.94	6.25	0.234	0.246
M	5 °NOM		5 °NOM	

GENERIC
MARKING DIAGRAM*



- DEV = Specific Device Code
- A = Assembly Location
- YY = Year
- WW = Work Week

*This information is generic. Please refer to device data sheet for actual part marking.

DOCUMENT NUMBER:	98ASB42125B	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.
STATUS:	ON SEMICONDUCTOR STANDARD	
NEW STANDARD:		
DESCRIPTION:	CASE 193-04, MICRODE	PAGE 1 OF 2

